

ABSTRACT

The present invention relates to a measuring system adapted for providing a measurement of an optical parameter of an optical device under test - DUT -, comprising a measuring instrument adapted to perform the measurement and

5 to provide a measurement signal comprising a plurality of values of the measured optical parameter of the DUT over the time.

To improve the measurement the measuring system is adapted to receive a temperature signal comprising a plurality of values of the measured temperature of the DUT over the time, and to provide an output signal wherein

10 values of the measured temperature are associated to such values of the measured optical parameter of the DUT that correspond in time.